

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HEYAN ET AL.	
		Examiner Paul E. Patton	Art Unit 2822	Page 1 of 1

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*	B	US-2003/0071350 A1	04-2003	Takehara et al.	257/728
*	C	US-6,384,701 B1	05-2002	Yamada et al.	333/247
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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